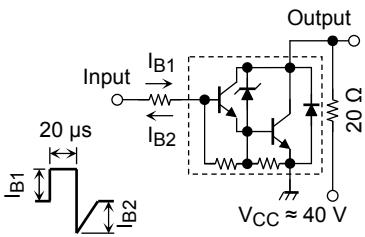
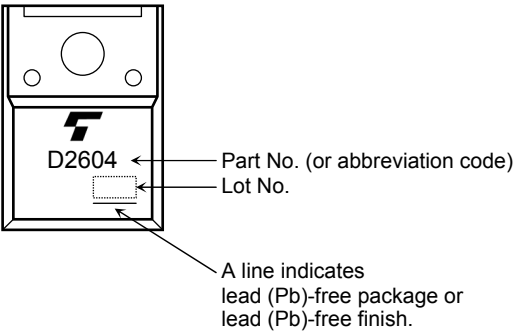
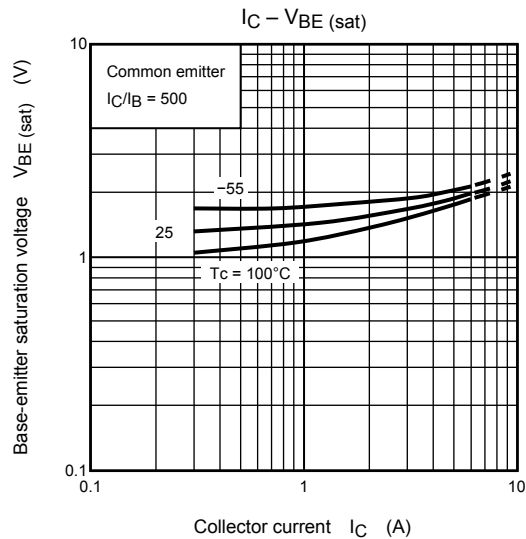
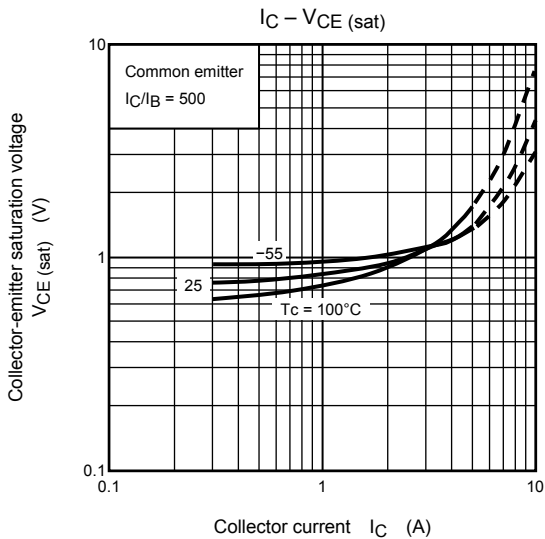
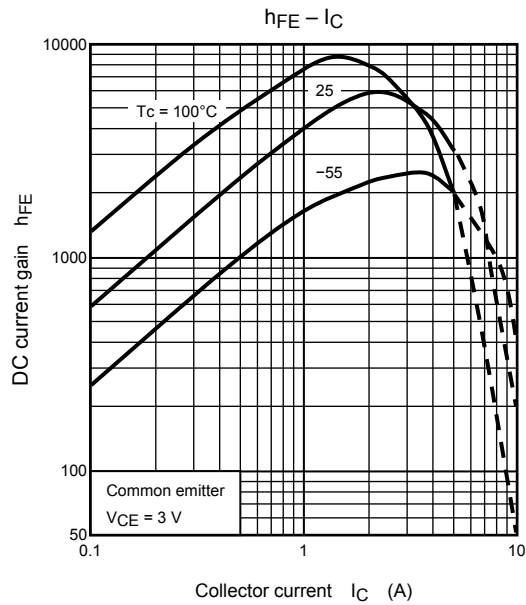
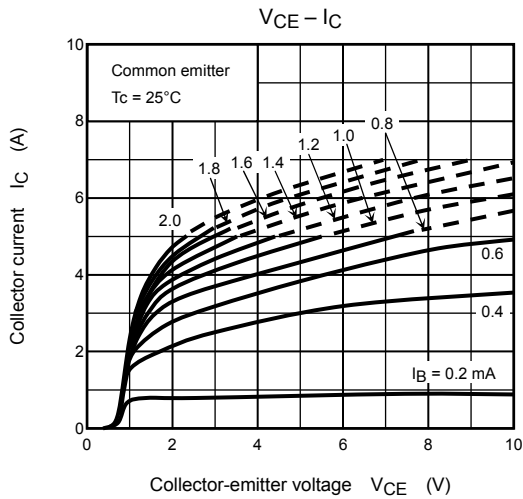


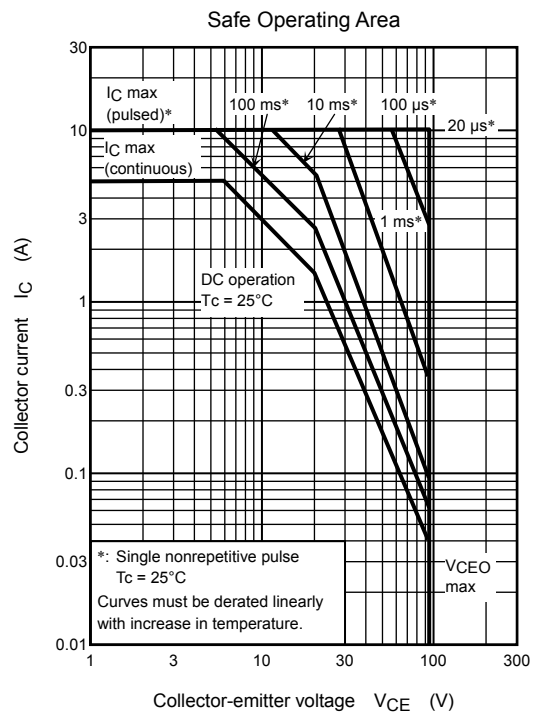
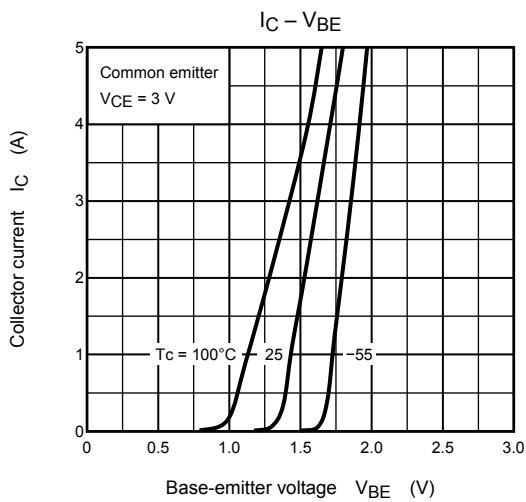
Electrical Characteristics (Tc = 25°C)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current		ICBO	V <sub>CB</sub> = 90 V, I <sub>E</sub> = 0	—	—	100	μA
Emitter cut-off current		IEBO	V <sub>EB</sub> = 6 V, I <sub>C</sub> = 0	0.75	—	3.0	μA
Collector-emitter breakdown voltage		V <sub>(BR)</sub> CEO	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 0	95	110	125	V
DC current gain	h <sub>FE</sub> (1)		V <sub>CE</sub> = 3 V, I <sub>C</sub> = 2 A	2000	—	15000	
	h <sub>FE</sub> (2)		V <sub>CE</sub> = 3 V, I <sub>C</sub> = 5 A	1000	—	—	
Collector-emitter saturation voltage		V <sub>CE</sub> (sat)	I <sub>C</sub> = 2 A, I <sub>B</sub> = 4 mA	—	0.9	1.5	V
Base-emitter saturation voltage		V <sub>BE</sub> (sat)	I <sub>C</sub> = 2 A, I <sub>B</sub> = 4 mA	—	1.5	2.5	V
Switching time	Turn-on time	t <sub>on</sub>	 I <sub>B1</sub> = -I <sub>B2</sub> = 4 mA, duty cycle ≤ 1%	—	0.5	—	μs
	Storage time	t <sub>stg</sub>		—	5.0	—	
	Fall time	t <sub>f</sub>		—	0.7	—	

Marking







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20070701-EN

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